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CONTINUING DATA

FOREIGN APPLICATIONS

JAPAN 2000-193104 08/27/2000
JAPAN 2000-229101 07/28/2000
JAPAN 2000-333834 11/02/2000
JAPAN 2001-11218 01/18/2001
JAPAN 2001-31901 02/08/2001
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Foreign Priority Claimed <input checked="" type="checkbox"/> 10 <input type="checkbox"/> 11 <input type="checkbox"/> 12 US USC 119 (b)-(3) conditions <input type="checkbox"/> 10 <input type="checkbox"/> 11 <input type="checkbox"/> 12 Inventor and Inventor's Address ADDRESS 71030 TITLE Inspection system by charged particle beam and method of manufacturing device using the system	STATE OR COUNTRY JAPAN	SHEETS DRAWING 30	TOTAL CLAIMS 60	INDEPENDENT CLAIMS 11
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